



$R_{DS(on),typ}$	$V_{GS}=4.5V$	44	$m\Omega$
I_D (Silicon Limited)		-26	A

Part Number	Package	Marking
HTD410P06	TO-252	TD410P06

Absolute Maximum Ratings at T_J

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	T_C	-26	A
		T_C	-18	A
	-	-60	V	
	-	± 20	V	
	-	-60	A	
	$L=0.1mH, T_C$	20	mJ	
		60	W	
		-55 to 175		

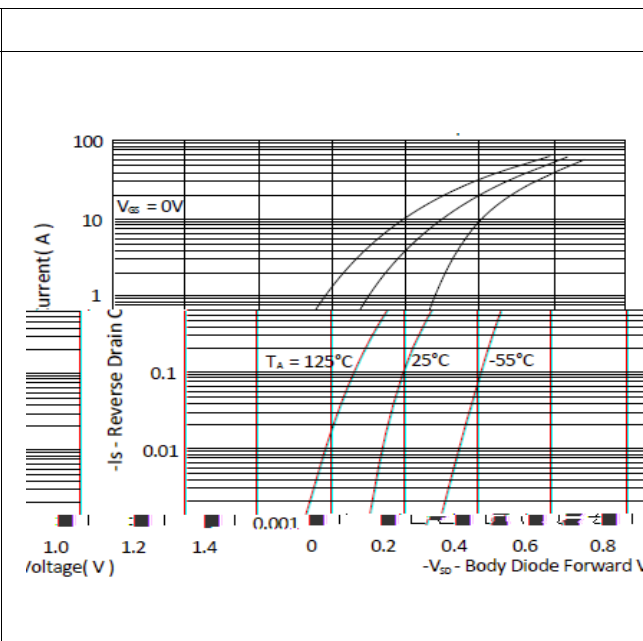
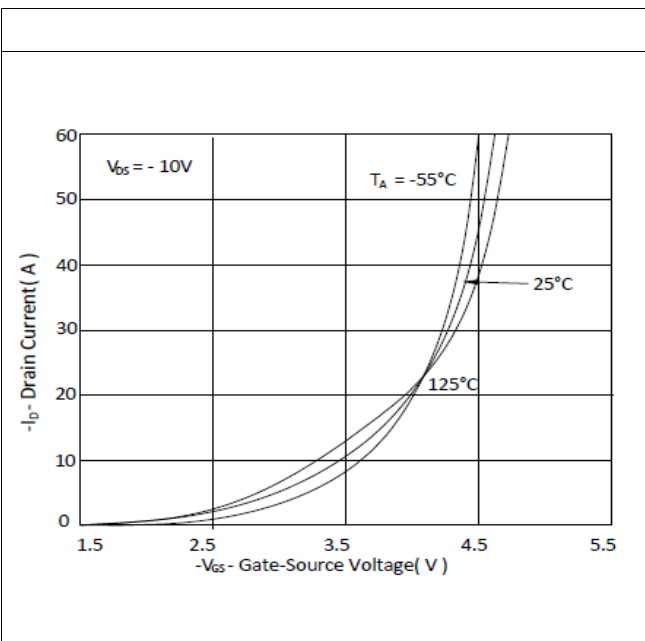
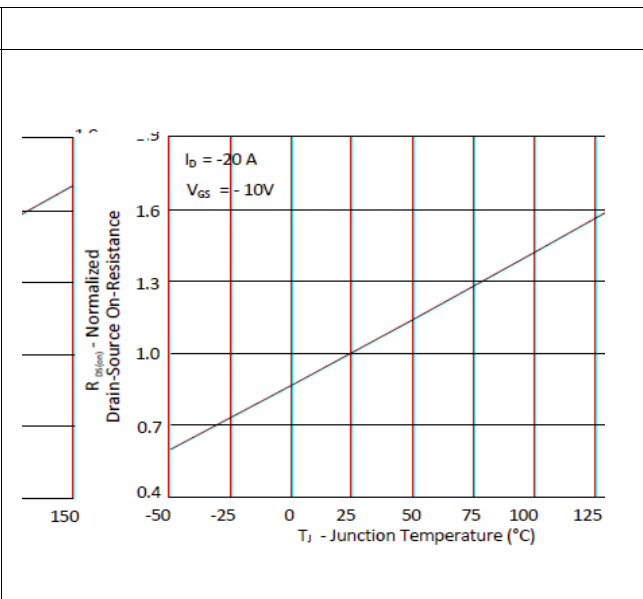
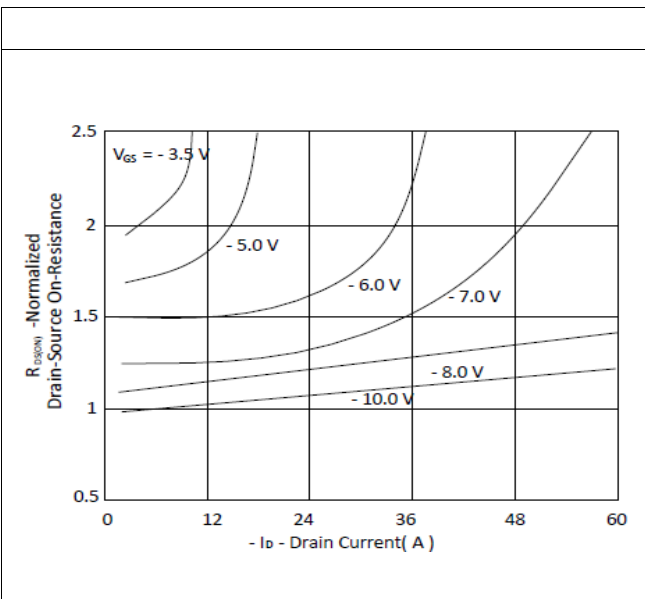
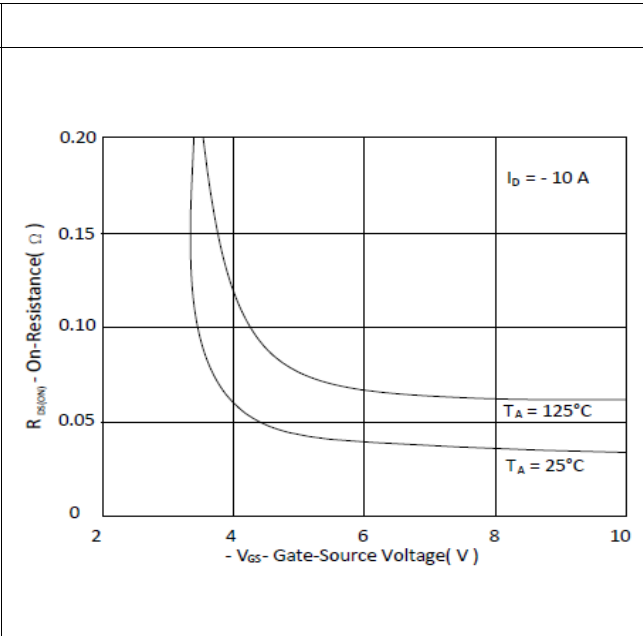
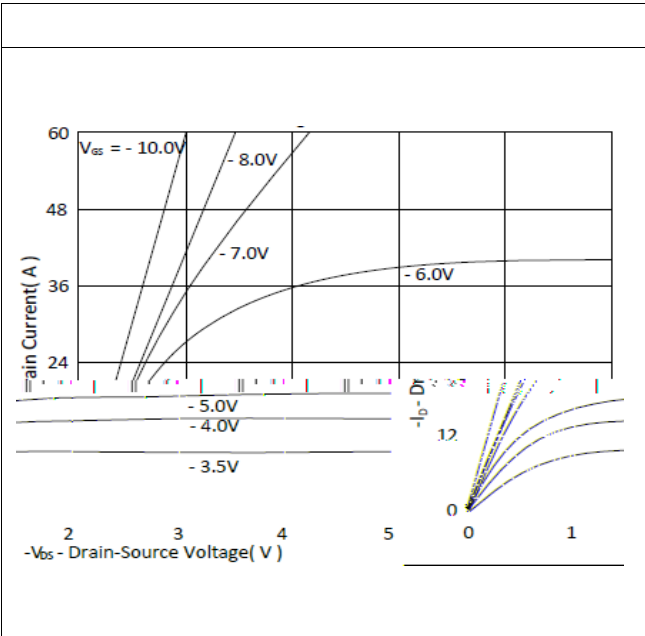
Absolute Maximum Ratings

Unit

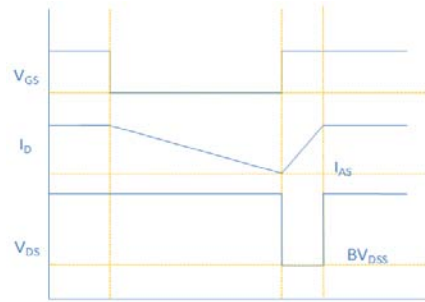
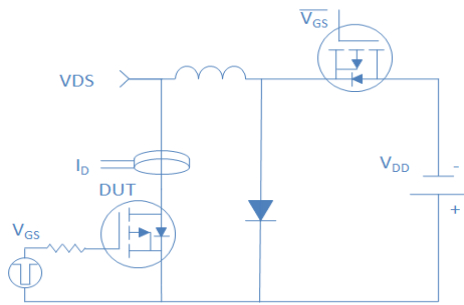
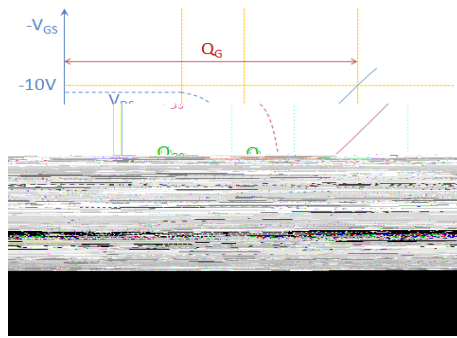
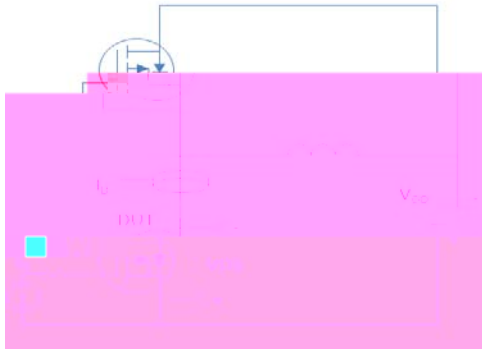
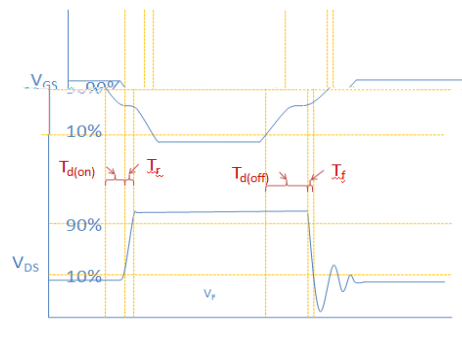
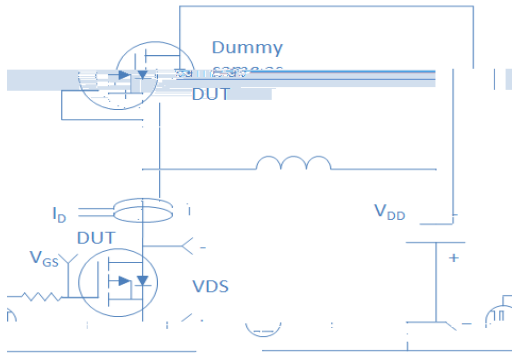
J

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Zero Gate Voltage Drain Current	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=-250\mu A$				
	V	$V_{GS}=V_{DS}, I_D=-250\mu A$				
Gate to Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS}=-48V, T_j$				
	I_{GSS}	$V_{GS}=0V, V_{DS}=-40V, T_j$				
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=\pm 20V, V_{DS}=0V$				
		$V_{GS}=-10V, I_D=-20A$				
Transconductance	g	$V_{DS}=-5V, I_D=-20A$				
Gate Resistance	R_G	$V_{GS}=15mV, V_{DS}$				
Input Capacitance	C_{iss}					
Output Capacitance	C_{oss}	$V_{GS}=0V, V_{DS}$				
	C_{rss}					
	$Q_g(10V)$					
	Q_{gs}	$V_{DD}=-30V, I_D=-20A, V_{GS}=-10V$				
	Q_{gd}					
Turn on Delay Time	$t_{d(on)}$					
Rise time	t_r	$V_{DD}=-10V, I_D=-1A, V_{GS}=-10V,$				
	t	$R_G=6\Omega,$	-	40	-	ns
	t		-	20	-	

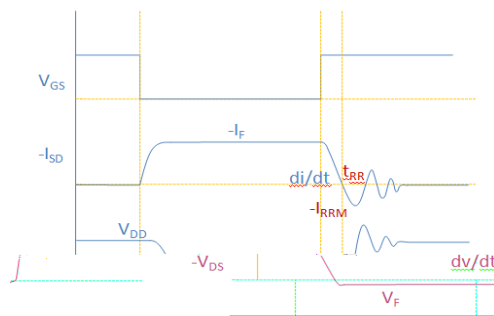
Reverse Recovery Time	V_{SD}		-		1.3	V
	t_{rr}		-	40	-	ns
	Q	μs	-	60	-	nC





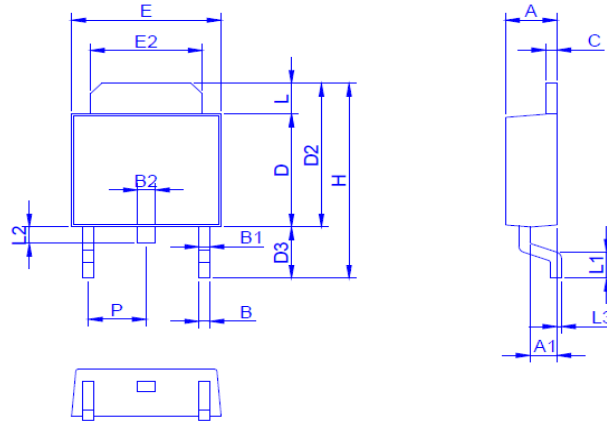


Diode Recovery Test



Package Outline

TO-252, 3leads



Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50